

Search Notes

Application/Control No.

10/659,276

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	373- 376,333,	11/15/2006	TL
D16	all	11/16/2006	TL
386	117-118,1	11/17/2006	TL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name search	11/15/2006	TL
US-PGPUB,USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB	11/15/2006	TL
INSPEC (same search key as in EAST)	11/15/2006	TL